Press release

Great expertise on small particles - expert days on particle characterization at LUM France

Berlin & Plaisir, 22 May 2025

On June 24th and 25th, LUM France and LUM GmbH are organizing the expert days on particle characterization at the LUM France headquarters in Plaisir (Paris). Customers from France are cordially invited to receive theoretical training on the measuring devices from LUM GmbH and to convince themselves of the advantages by measuring their own samples. This time the focus is on the LUMiSpoc®.

The LUMiSpoc® is an advanced single-particle analysis system, similar to a flow cytometer, that measures the particle size distribution and particle concentration of nano- and microparticles in suspensions and emulsions with unprecedented resolution and dynamic range. The instrument uses patented SPLS Technology®, a technology that records light scattered by individual nano- and micro-particles in forward and sideways directions while transmitting a laser beam with a specific beam cross-section. It provides a deep insight into complex nano and submicro particle systems that can be used to design tailored particles and dispersions.

The experts Elia Wollik and Sylvain Gressier will give lectures on site. Elia Wollik is a Senior Product Specialist at LUM GmbH, specializing in nanoparticle analysis and optical measurement techniques. His work focuses on the further development and optimization of analytical instruments, the identification of new areas of application and the support of research and development collaborations as well as customer-specific sample analyses. He was significantly involved in the development and market launch of the LUMiSpoc®. Elia Wollik has a master's degree in pharmaceutical and chemical technology with a focus on particle analysis and light scattering.

Sylvain Gressier, graduate of the University of Evry Val d'Essonne in human genetics, then field representative and long-time manager of the French subsidiary of LUM GmbH, has 13 years of unparalleled practical and theoretical experience in the use of LUM measuring devices for micro- and nanoparticle characterization in France, for direct accelerated stability tests of dispersions and emulsions and for materials testing. By collaborating with industrial companies and participating in international scientific and academic symposia and conferences, he aligns the needs of users with LUM's current and future technical and commercial solutions. At the 14th World Filtration Congress (WFC 14) in Bordeaux from June 30th to July 4th, Sylvain Gressier will give a lecture on the topic: Filtration efficiency monitored by particle counting and sizing using Single Particle Light Scattering Technology® (SPLS).

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